

Search Notes



Application/Control No.

10/631,057

Examiner

Quoc A. Tran

Applicant(s)/Patent under Reexamination

DINH ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	501.1	9/28/2005	
455	412.1	9/28/2005	
707	102	9/28/2005	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
INVENTORS SEARCH CHECK FOR DOUBLE PATENT	9/28/2005	
EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) see Search Histoty Printout	9/28/2005	
NPL IEEE DataBase see Search History Printout	9/28/2005	